Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(716/8).ccls. and ((effectiveness) same ((electrostatic adj discharge) or ESD)) and (EDS adj event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:31
L2	0	(716/8).ccls. and ((effectiveness) same ((electrostatic adj discharge) or ESD)) and (ESD adj event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:31
L3	0	(716/8).ccls. and (((effectiveness) same ((electrostatic adj discharge) or ESD)) same event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:32
L4	0	(716/8).ccls. and ((((electrostatic adj discharge) or ESD)) same event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:33
L5	0	(716/2).ccls. and ((((electrostatic adj discharge) or ESD)) same event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:33
L6	0	(716/9).ccls. and ((((electrostatic adj discharge) or ESD)) same event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:33
L7	0	(716/10).ccls. and ((((electrostatic adj discharge) or ESD)) same event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:33
L8	0	("716"/$).ccls. and (((((electrostatic adj discharge) or ESD)) same event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:33
L9	26	(((((electrostatic adj discharge) or ESD)) same event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:35
L10	25	(((((electrostatic adj discharge) or ESD)) near event) and (current adj source) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:37

L11	5	(((((electrostatic adj discharge) or ESD)) near event) same (current adj source)) and (voltage adj threshold)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:54
L12	5	(((((electrostatic adj discharge) or ESD)) near event) same (current adj source)) and (voltage adj threshold) and resistor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:57
L13	0	(((((electrostatic adj discharge) or ESD)) near event) same (current adj source)) and (ESD same (voltage adj source)) and (voltage adj threshold) and resistor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:57
L14	1	(((((electrostatic adj discharge) or ESD)) near event) same (current adj source)) and (voltage adj source) and (voltage adj threshold) and resistor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 13:02
L15	0	model$4 and (((((electrostatic adj discharge) or ESD)) near event) same (current adj source)) and (voltage adj source) and (voltage adj threshold) and resistor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 13:02
S1	1250	716/8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:41
S2	653	716/9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:41
S3	1133	716/10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:41
S4	1686	716/2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:41
S5	19	(716/8).ccls. and ((electrostatic adj discharge) oe ESD) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:56

S6	0	(716/8).ccls. and ((list or set or gtoup) adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:57
S7	0	(716/8).ccls. and ((list or set or group) adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 12:28
S8	0	(716/9).ccls. and ((list or set or group) adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:58
S9	1	(716/10).ccls. and ((list or set or group) adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:58
S10	0	(716/2).ccls. and ((list or set or group) adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 10:58
S11	2	("716"/$).ccls. and ((list or set or group) adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:02
S12	19	((list or set or group) adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:25
S13	0	(((list or set or group) adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:05
S14	0	(preferred adj ((electrostatic adj discharge) or ESD)) and (region$2 or area$2 or location$2) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:25

S15	15	((electrostatic adj discharge) or ESD) and ((preferred or ideal or optimal) adj (region$2 or area$2 or location$2)) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:27
S16	15	((electrostatic adj discharge) or ESD) and ((preferred or ideal or optimal) adj (region$2 or area$2 or location$2)) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:28
S17	2	(((electrostatic adj discharge) or ESD) same ((preferred or ideal or optimal) adj (region$2 or area$2 or location$2))) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:30
S18	0	(((electrostatic adj discharge) or ESD) near ((preferred or ideal or optimal) adj (region$2 or area$2 or location$2))) and (placement or placing or locating or locate) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:31
S19	0	((((electrostatic adj discharge) or ESD) and ((preferred or ideal or optimal) adj (region$2 or area$2 or location$2))) and (placement or placing or locating or locate) and (circuit)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:30
S20	0	(((electrostatic adj discharge) or ESD) near ((preferred or ideal or optimal) adj (region$2 or area$2 or location$2))) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:31
S21	3	(((electrostatic adj discharge) or ESD) same ((preferred or ideal or optimal) adj (region$2 or area$2 or location$2))) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/07 11:31

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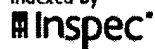|	
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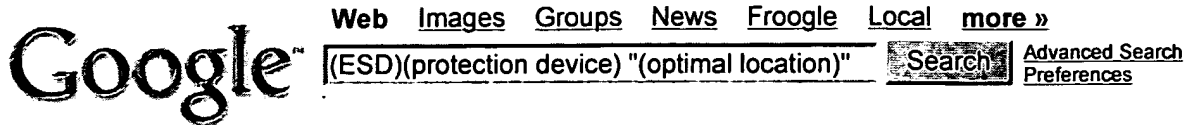Please edit your search criteria and try again. Refer to the Help pages if you need assistan
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